

**An Investigation of the Impedance Rise  
in High-Power Li-ion Cells**

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The Advanced Technology Development Program (ATD) was established by the US Department of Energy to investigate key issues affecting the calendar and cycle life of high-power lithium-ion batteries. These issues include impedance rise and power fade.

For the purposes of this study, two different lots of 18650-sized cells (hereafter called Gen 1 and Gen 2) were built to our specifications containing commercially available chemistries. They were subjected to accelerated calendar and cycle life tests according to standards established by the Partnership for a New Generation of Vehicles (PNGV). The Gen 1 cells were life tested at three temperatures (40, 50 and 60°C) and two states of charge (SOC) (40 and 60%). The Gen 2 cells were life tested at 45 and 55°C and at 60% SOC.

As a part of PNGV testing, the cells were initially characterized by undergoing a series of performance tests, including the hybrid pulse power characterization<sup>1</sup> (HPPC). The cells were then aged at the desired temperatures for 4-week periods. At the end of 4 weeks, the cells were cooled to 25°C and the performance tests were repeated to determine how the power capability of the cells changed during the time at temperature.

Area-specific impedance and power values were calculated from the HPPC results for each Gen 1 and Gen 2 cell. From these results, the percent changes were averaged and plotted versus time. The Gen 1 calendar life cells were found to follow Arrhenius and (time)<sup>0.5</sup> kinetics. A detailed discussion of the Gen 1 results appears in the literature.<sup>2</sup> Figure 1 shows the time dependencies of the Gen 2 calendar-life cells tested at 45 and 55°C. The Gen 2 calendar- and cycle-life cells at 45°C appear to follow (time)<sup>0.5</sup> kinetics, which is ascribable to thin-film, SEI layer, formation. The calendar life cells at 55°C, however, appear to follow a different kinetic law, linear with time.

In order to understand some of the more basic reasons for these time dependences, the 60%-SOC HPPC data were modeled using the Lumped Parameter Model.<sup>3</sup> This model linearizes the pulse response characteristics in terms of ohmic and polarization resistances (R<sub>o</sub> and R<sub>p</sub>, respectively) and capacitances.

Using the Gen 1 and Gen 2 calendar life cell data, we found that R<sub>o</sub> dominates in both cases. For the Gen 1 cells, the time dependence of R<sub>o</sub> was (time)<sup>0.5</sup>. The time-dependence of R<sub>p</sub> was more complex. At 40°C, R<sub>p</sub> was linear with time; above 40°C, it depended on (time)<sup>0.5</sup> at both 40 and 60% SOC storage conditions.

For the Gen 2 calendar life cells, temperature-dependence was also found. The time dependence of R<sub>o</sub> and R<sub>p</sub> for the Gen 2 calendar-life cells tested at 55 and 45°C are shown in Figs. 2 and 3, respectively. R<sub>o</sub> was linear with time at 55°C and depended on (time)<sup>0.5</sup> at 45°C. R<sub>p</sub> was linear with time at 55°C and almost time-independent at 45°C. For the Gen 2 cycle life cells, R<sub>o</sub> depended on (time)<sup>0.5</sup> and R<sub>p</sub> had a slight time dependence.

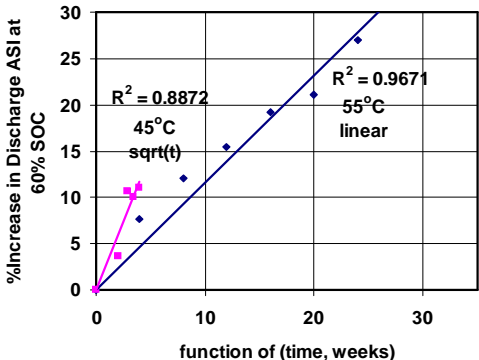


Fig. 1. Time-dependencies of Gen 2 calendar life cells at 45 and 55°C.

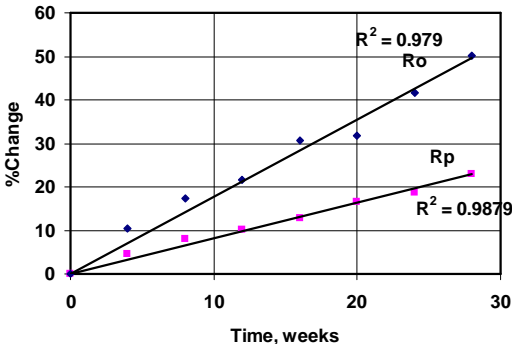


Fig. 2. Time dependencies of R<sub>o</sub> and R<sub>p</sub> for Gen 2 calendar life cells at 55°C.

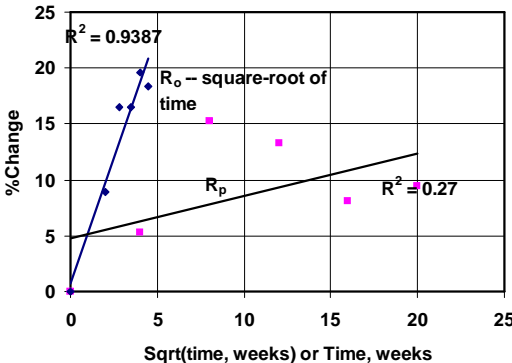


Fig. 3. Time dependencies of R<sub>o</sub> and R<sub>p</sub> for Gen 2 calendar life cells at 45°C.

<sup>1</sup> PNGV Test Manual, DOE/ID-10597, Rev. 2 (August 1999) and Rev. 3 (February 2001).  
<sup>2</sup> I. Bloom, et al, *J. Power Sources*, 101 (2001) 238-247.  
<sup>3</sup> PNGV Test Manual, Rev. 3, p. D-4.